

## **ABSTRACT OF THE DISCLOSURE**

2 The present invention relates to a memory interlace-checking method and, in  
3 particular, to a test method that can effectively detect the weakening of memory.  
4 This test method is different from the conventional continuous address testing style.  
5 It is an interlacing address test method that comprises a main step and a data  
6 checking step. The main step provides main data to perform command actions on  
7 local addresses in memory. This will weaken other portions in the memory that are  
8 not triggered by commands because of the electromagnetic interference (EMI)  
9 induced by memory operations. Afterwards, in the data checking step, the yet to be  
10 triggered portion will be checked in a complementary way in order to accurately  
11 detect weakened memory.

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